Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/941,541	INOUE, SATOSHI
Examiner	Art Unit
Jennifer T. Nguyen	2674

	SEAR	CHED	
Class	Subclass	Date	Examiner
345	107	510/05	JW
	84		
	85		
	86	·	
359	296		
	197		
204	600		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Same a	s above	5/10/05	JN		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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